IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Katsuhiko Fukasaku

Serial No.: Not Yet Assigned Group Art Unit: Not Yet Assigned

Filing Date: Concurrently Herewith Examiner: Unknown

For: SEMICONDUCTOR DEVICE AND METHOD FOR MANUFACTURING THE

SAME

Assistant Commissioner of Patents

Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Prior to examination on the merits and calculation of the filing fee, please amend the above-identified application as follows:

IN THE SPECIFICATION:

Please amend the paragraphs beginning at page 7, lines 3-16 as follows:

FIGS. 1(A)-1(D) are process diagrams for showing a method for manufacturing an NMOSFET device according to a first embodiment of the present invention;

FIGS. 2(E)-2(H) are continued process diagrams for showing a method for manufacturing the NMOSFET device according to the first embodiment of the present invention;

FIGS. 3(I)-3(L) are further continued process diagrams for showing the method for manufacturing the NMOSFET device according to the first embodiment of the present

NE253-US

invention;

FIGS. 4(A)-4(D) are process diagrams for showing a method for manufacturing an NMOSFET device according to a second embodiment of the present invention;

FIGS. 5(A)-5(D) are process diagrams for showing a method for manufacturing a prior art NMOSFET device; and

REMARKS

The specification has been amended to indicate the identity of Figures 1(A)-1(D) through 5(A)-5(D).

Attached hereto is a marked-up version of the changes made to the specification by the current Amendment. The attached pages are captioned "Version with markings to show changes made."

Early, favorable prosecution on the merits is respectfully requested.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,

Sean M. McGinn

Registration No.: 34,386

Date: <u>January 18, 2002</u> McGinn & Gibb, PLLC 8321 Old Courthouse Road; Suite 200 Vienna, Virginia 22182-3817 (703) 761-4100 Customer No. 21254

VERSION WITH MARKINGS TO SHOW CHANGES MADE

In the Specification:

Please amend the paragraphs beginning at page 7, lines 3-16 as follows:

[FIG.1] <u>FIGS. 1(A)-1(D)</u> [is a process diagram] <u>are process diagrams</u> for showing a method for manufacturing an NMOSFET device according to a first embodiment of the present invention:

[FIG.2] <u>FIGS. 2(E)-2(H)</u> [is a continued process diagram] <u>are continued process</u> <u>diagrams</u> for showing a method for manufacturing the NMOSFET device according to the first embodiment of the present invention;

[FIG.3] <u>FIGS. 3(I)-3(L)</u> [is a further continued process diagram] <u>are further continued</u> <u>process diagrams</u> for showing the method for manufacturing the NMOSFET device according to the first embodiment of the present invention;

[FIG.4] <u>FIGS. 4(A)-4(D)</u> [is a process diagram] <u>are process diagrams</u> for showing a method for manufacturing an NMOSFET device according to a second embodiment of the present invention;

[FIG.5] <u>FIGS. 5(A)-5(D)</u> [is a process diagram] <u>are process diagrams</u> for showing a method for manufacturing a prior art NMOSFET device; and